FORM PTO-1449	Attorney Docket Number	39260/RAG/C766
	Application Number	09/547,790
INFORMATION DISCLOSTRE	Filing Date	April 12, 2000
STATEMENT BY APPLICANT SP 0 7 2000	Applicant(s)	Francis M. Reininger
(use as many sheets a necessary)	Group Art Unit	2877
(use as many sheets as necessary)	Examiner Name	To be determined

U.S. PATENT DOCUMENTS						
EXAMINER INITIALS	DOCUMENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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(m)	4,523,846	06/1985	Breckinridge et al.	356	346	
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		FOREIGN	PATENT DOCUME	NTS			_
EXAMINER INITIALS	DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANS YES	NO NO

	OTHER DOCUMENTS
EXAMINER INITIALS	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
GN	Hirst et al., "Optical sensors: a path to better gas detection", Global Challenges, Physics World, August 1998, pp. 37-40
GW	DOHI ET AL., "Attainment of High Resolution Holographic Fourier Transform Spectroscopy", Applied Optics, May 1971, pp 1137-1140, Vol. 10, No. 5
GW	STROKE ET AL., "Fourier-Transform Spectroscopy Using Holographic Imaging Without Computing and With Stationary Interferometers", Physics Letters, June 1, 1965, pp. 272-274, Vol. 16, No. 3
(M	BARNES, "Photodiode array Fourier transform spectrometer with improved dynamic range", Applied Optics, November 15, 1985, pp. 3702-3706, Vol. 24, No. 22,
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

419A/B	Attorney Docket Number	39260/JWP/C766
DISCEOSURE	Application Number	09/547,790
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		U.	S. PATENT DOCUMENTS	3
EXAMINER INITIALS	Cite No.	DOCUMENT NUMBER Number - kind code <sup>2</sup> - (If known)	PUBLICATION DATE MM-DD-YYYY	NAME OF PATENTEE
GW		5,266,795	11/30/1993	Vaughan
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EXAMINER INITIALS	Foreign Patent Document Country Code <sup>3</sup> - Number <sup>1</sup> - Kind Code <sup>5</sup> (If known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	T'' ( <b>⁄</b> )

		OTHER DOCUMENTS
EXAMINER INITIALS	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
Gw		FLAMINI, Enrico et al.; Remote mineralogy through multispectral imaging, the VIMS-V instrument; 10 pp.
6N		LOBB, D.R.; Theory of concentric designs for grating spectrometers; Applied Optics; May 1, 1994; Vol. 33, No. 13, pp. 2648-2658
Gw		MERTZ, L.; Concentric spectographs; Applied Optics; December 1977; Vol. 16, No. 12; pp. 3122-3124
GW		OFFNER, A.; New Concepts in Projection Mask Aligners; Optical Engineering; March-April 1975; Vol. 14, No. 2; pp. 130-132
aw		REININGER, Francis; Near ultraviolet visible infrared mapping spectrometer (NU-VIMS); SPIE; 1994; Vol. 2209; pp. 332-344

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FORM PTO/SB/08A/B (10-01) MAR 1 2 2002 Substitute for PTO-1449A/B	Attorney Docket Number	39260/JWP/C766
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	т	OTHER DOCUMENTS
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Gw		REININGER, Francis; VIRTIS: Visible Infrared Thermal Imaging Spectrometer for the Rosetta mission; SPIE; 1996; Vol. 2819; pp. 66-77
6W		REININGER; Francis et al.; Visible infrared mapping spectrometer-visible channel (VIMS-V); SPIE; 1994; Vol. 2198; pp. 239-250

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